

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10599107	TAGAWA ET AL.
Examiner	Art Unit	
Son T Nguyen	3643	

SEARCHED

Class	Subclass	Date	Examiner
47	1.01P,1.01R,1.7	4/8/10	stn
111	114,104,105	4/8/10	stn
414	416.09,416.11	4/8/10	stn
198	468.6	4/8/10	stn

SEARCH NOTES

Search Notes	Date	Examiner
Foreign IPC search, see printouts	4/8/10	stn
Consulted with primaries J.Keenan (class 414) and J.Bidwell (class 198)	4/8/10	stn

INTERFERENCE SEARCH

Class	Subclass	Date	Examiner